DAMAGE OF SOLIDS INDUCED BY SINGLE PULSES OF XUV-FLASH

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Keywords: XUV FEL, radiation damage, ablation, structure modifications, x-ray diffraction, pump and probes

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The VUV- and XUV-FEL beam interaction with matter has been extensively investigated for the last few years with a special attention paid to the damage induced in solids. Most of this work was performed with the Free electron LASer in Hamburg (FLASH). This new type of the IVth generation SR source delivers intense pulses of coherent light in the wavelength range of 6 - 50 nm with the unique combination of quantum energy, extreme short pulse duration of only 25 fs and high power/pulse up to 5 GW. Application of the radiation opens up an access to study not yet explored phenomena, remaining unattainable with classical sources.

Interaction of XUV FLASH pulses with solids can change optical properties of the materials and induces complex damage processes leading to the formation of specific morphological structures with sizes on micrometric and nanometric scales [1, 2]. The absorbed pulse energy can also provoke phase transitions that change composition or crystalline state of the near-surface material [3]. Investigation of these phenomena is crucial for refinement of theoretical models, necessary to predict performance and lifetime of optical components for the new generation of FELs operating in the XUV and X-ray region.

In this work we put together some of our important experimental results, obtained with aid of various techniques, on the interaction of high intensity $(10^{11} - 10^{14} \text{ W/cm}^2)$ ultrashort pulses, delivered by FLASH, with solids. The one-color pump and probe technique made it possible to probe fluency-dependent variations in the optical constants of materials on the time scales of a single pulse duration.

The dynamics of ablation process was studied on the sample surface by the two-color pump and probe method with aid of an external optical laser. A detailed *ex-situ* characterization of irradiation-induced modifications on the solid surfaces was obtained by mixing the traditional microscopic methods with AFM. The x-ray microdiffraction with submicrometer beam was applied to probe the crystalline state with lateral resolution of only 250 nm.

By combining the results obtained with various experimental techniques, a more comprehensive picture of the processes in solids excited by an intense femtosecond XUV pulse was achieved.

Acknowledgements: This work has been partially supported by the Ministry of Science and Higher Education of Poland, SPB nr. DESY/68/2007, by the Czech Ministry of Education from the National Research Centers program (Projects LC510 and LC528) and program INGO (Grant LA08024) and by Academy of Sciences of the Czech Republic (Grants Z10100523, IAA400100701, and KAN300100702). Irradiation with FLASH has been performed within the framework of the *Peak-Brightness-Collaboration* [project II-20022049 EC]. Support from the PBC and the operators of the FLASH facility are gratefully acknowledged. The synchrotron measurements at HASYLAB, Hamburg were supported by the RIA FP6 Contract RII3-CT-2004-506008 of the European Community, The microdiffraction study has been done at the ID-13 beamline at ESRF, Grenoble.

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